

Amendments to the Abstract:

~~ABSTRACT~~ ABSTRACT OF THE DISCLOSURE

~~There are provided a~~ A semiconductor memory device incorporating ~~incorporates~~ an ECC circuit which enables an efficient test of the device with high accuracy ~~by using~~ a simplified structure, and which can shorten the test time ~~and a test method thereof. A semiconductor memory device has an.~~ The ECC circuit is capable of correcting, from an m-bit information code and an n-bit check code that have been stored in an information storing part, an error of the information code to x bits, and a parallel test circuit is provided for receiving an information code and a check code for the test with the same bits stored in the information storing part and ~~deciding for determining that a product having a defect with the x+1 bits or more as being~~ is defective. The parallel test circuit ~~decides~~ determines that a chip having a defect with the x+1 bits or more for one piece of position information as ~~a~~ is defective chip.